

CYPRESS SEMICONDUCTOR CORPORATION PRODUCT RELIABILITY REPORT

QUARTER 3, 1997



PERFORM PER THE REQUIREMENT OF 25-00008, RELIABILITY MONITOR PROGRAM SPECIFICATION

Marc Hartranft
QA Engineering Department Manager

STANDARD STRESS TEST DESCRIPTIONS

<u>TEST</u>	<u>DESCRIPTION</u>
HTOL	High Temp Op Life, 150°C, 5.75V
HTOL2	High Temp Op Life, 125°C, 5.75V
HTSSL	High Temp Steady State Life, 150°C, 5.75V
HTSSL2	High Temp Steady State Life, 125°C, 5.75V
DRET	Data Retention Test, Data Bake 165°C, Plastic
DRET2	Data Retention Test, Data Bake 250°C, Hermetic
PCT	Pressure Cooker Test, 121°C, 100%RH, No Bias
HAST	Hi-Accel Saturation Test, 140°C, 85%RH, 5.5V Bias
TC	Temp Cycle, 125°C to -40°C
TC2	Temp Cycle, 150°C to -65°C
HTS	High Temp Storage, 165°C, No Bias
TEV	Temperature Extreme Verification

WAFER FAB AREAS

<u>FAB #</u>	<u>LOCATION</u>
CA	San Jose, California
TX	Round Rock, Texas
MN	Bloomington, Minnesota
FR	MHS, France

ASSEMBLY LOCATION

<u>ID</u>	<u>COMPANY/LOCATION</u>
KOREA-A	Anam-Buchon/Korea
ASAT-B	Asat/Hongkong
USA-C	Cypress/USA
PHIL-D	Dynesem/Philippines
USA-E	Cypress-Minnesota/USA
INDNS-F	Astra/Indonesia
TAIWAN-G	ASE/Taiwan
KOREA-H	Hyundai/Korea
MALAY-J	ASE/Malaysia
THLAND-K	TMS/Thailand
KOREA-L	Anam-Seoul/Korea
PHIL-M	Anam/Philippines
USA-N	Express/USA
INDNS-O	Omedata/Indonesia
USA-P	Pantronix/USA
KOREA-Q	Anam-Bupyong/Korea
PHIL-R	Cypress/Philippines
USA-S	ATM/USA
TAIWAN-T	OSE/Taiwan
MALAY-U	Unisem/Malaysia
USA-V	Aplus/USA
USA-W	Toshiba/USA
ALPHA-X	Cypress Bangkok/Thailand
ALPHA-Y	Alphatech/Thailand
THLAND-Z	Hana/Thailand

DESCRIPTION OF DATA TABLE COLUMN HEADINGS

<u>COLUMN HEADING</u>	<u>DESCRIPTION OF COLUMN CONTENTS</u>
Division	Cypress Manufacturing Division
Test	Common code for the stress performed. See table on previous page for detail.
Test Condition	Tem/humidity/bias condition for the stress. See table on previous for detail
Device ID	Cypress part number
Date Code	Week in which specific lot was marked/sealed/molded.
Lot Number	Manufacturing (assembly) lot number
Function	Generic product family at Cypress
Description	Brief description of device function
Technology	Fabrication process technology.
Process	Generic fabrication process
Pkg Material	Generic packaging material
Pkg Type	Common code for standard package configuration (PDIP=Plastic Dual-In-Line-Package).
Pkg Location	Country Location + Initial of assembly house (see table on previous page for detail).
# Pins	Pin cont of package in which device is assembled.
Duration	Data Readpoint of stress. For Temp Cycle (TC) = Cycles; all other stresses=Hours.
# Test	Quantity of devices submitted to this stress/test.
# Failed	Quantity of devices failing at this specific readpoint.
Fail Mode	Failure analysis results from this test, if any.

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Division	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Function	Description	Technology	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
CPD	DRET	165C/NO BIAS	CY7C611A-NC	M72016	9708	349700966	VME	RISC CONTRL	SRAM/LOGIC-L20	CMOS	TX	PQFP	HK-B	160	336 1000	78 78	0 0	
			CY7C63101-SC	96514	9714	219703088	USB	USB	FAMOS-P26	CMOS	TX	SOIC	ALPHA-X	24	168 552	76 76	0 0	
	DRET2	250C/NO BIAS	CY7C63101-WC	96514	9714	219703142	USB	USB	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	24	96	76	0	
HAST	130C/5.5V		CY82C693-NC	97114	9713	619701790	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	128 256	48 48	0 0	
				97135	9713	619701790	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	128 256	48 48	0 0	
	140C/5.5V	CY2308ZC	97151	9720	349702279	TTECH	DELAY BUF.	SRAM/LOGIC-L28	CMOS	MN	TSOP	PHIL-M	16	128	48	0		
		CY7C63101-SC	96514	9714	219703088	USB	USB	FAMOS-P26	CMOS	TX	SOIC	ALPHA-X	24	128	45	0		
HTOL	150C/5.5V		CY7C63101-SC	96514	9714	219703088	USB	USB	FAMOS-P26	CMOS	TX	SOIC	ALPHA-X	24	48 48	482 545	0 1	3 EOS 1 SINGLE BIT
				9718	219704292	USB	USB	FAMOS-P26	CMOS	TX	SOIC	ALPHA-X	24	48 80 500	476 114 114	0 0 0	2 EOS	
				9727	219706999	USB	USB	FAMOS-P26	CMOS	TX	SOIC	ALPHA-X	24	48 48	478 545	0 0		
	150C/5.75V	CY7C63101-SC	96514	9718	219704292	USB	USB	FAMOS-P26	CMOS	TX	SOIC	ALPHA-X	24	48	476	0		
		CY82C693-NC	97114	9713	619701790	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	48 80 500	122 78 78	0 0 0	3 EOS	
				619701791	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	48 80 500	124 78 78	0 0 0	1 EOS		
HTS	165C/NO BIAS		CY2308ZC	97151	9720	349702279	TTECH	DELAY BUF.	SRAM/LOGIC-L28	CMOS	MN	TSOP	PHIL-M	16	336 1000	48 48	0 0	
			CY82C693-NC	97135	9724	349703236	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	336	45	0	

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Division	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Function	Description	Technology	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode
CPD	HTS	165C/NO BIAS	CY82C693-NC	97135	9724	349703236	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	500 1000	45 44	0 0	
	HTSSL	150C/5.75V	CY7C63101-SC	96514	9714	219703088	USB	USB	FAMOS-P26	CMOS	TX	SOIC	ALPHA-X	24	168	75	0	1 EOS
			CY82C693-NC	97114	9713	619701790	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	80 80 168 168 168	48 75 30 48 74	0 0 0 0 0	0 1 EOS
						619701791	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	80 168	76 76	0 0	
	PCT	121C/100%RH	CY7C611A-NC	M72017	9708	349700966	VME	RISC CONTRL	SRAM/LOGIC-L20	CMOS	TX	PQFP	HK-B	160	96 168	79 75	4 4	4 TOPSIDE CRACKS
	T/S	-55C TO 150C	CY2308ZC	97151	9720	349702279	TTECH	DELAY BUF.	SRAM/LOGIC-L28	CMOS	MN	TSOP	PHIL-M	16	100 200	48 48	0 0	
			CY82C693-NC	97135	9713	619701790	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	100 200	48 48	0 0	
	TC	-40C TO 125C	CY7C611A-NC	M72015	9708	349700966	VME	RISC CONTRL	SRAM/LOGIC-L20	CMOS	TX	PQFP	HK-B	160	500 1500	48 47	1 0	1 UNKNOWN
	TC2	-65 TO 150C	CY7C63101-WC	96514	9714	219703142	USB	USB	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	24	100 1000	45 45	0 0	
		-65C TO 150C	CY2308ZC	97151	9720	349702279	TTECH	DELAY BUF.	SRAM/LOGIC-L28	CMOS	MN	TSOP	PHIL-M	16	300 300 300 300	48 48 48 48	0 0 0 0	
			CY7C63101-SC	96514	9714	219703088	USB	USB	FAMOS-P26	CMOS	TX	SOIC	ALPHA-X	24	300 1000	45 45	0 0	
			CY82C693-NC	97114	9713	619701790	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	300 1000	47 47	0 0	
						619701791	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	300 1000	48 48	0 0	

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CPD	TC2	-65C TO 150C	CY82C693-NC	97114	9724	349703236	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	300	48	0	
				97135	9713	619701790	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	300 1000	47 47	0 0	
						619701791	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	300 1000	48 48	0 0	
					9724	349703236	PCLOG	PC CHIPSET	SRAM/LOGIC-L27	CMOS	MN	PQFP	MALAY-J	208	300	48	0	
			VIC068A-BC	M72018	9713	349701655	VME	VME INTERF.	SRAM/LOGIC-C2AN	CMOS	MN	PPGA	PHIL-M	144	300 1000	50 50	0 0	

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DCD	HAST	130C/5.5V	CY7C4245-AC	M72059	9703	349700347	SPCM	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	64	128	35	0		
															128	45	0		
			CY7C136-JC	M73047	9718	349702681	SPCM	2K x 8 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	PHIL-M	52	128	22	0		
		140C/5.5V	CY7C136-JC	M73047	9718	349702681	SPCM	2K x 8 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	PHIL-M	52	128	22	0		
			CY7C4265-JC	96464	9706	349700756	SPCM	16KX18 FIFO	SRAM/LOGIC-R30	CMOS	MN	PLCC	PHIL-M	68	128	91	0	2 EOS	
HTOL	150C/5.75V		CY7C0251-AC	97318	9728	619704595P	SPCM	8K x 16 DP	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	100	48	398	0		
			CY7C4265-JC	96464	9706	349700756	SPCM	16KX18 FIFO	SRAM/LOGIC-R30	CMOS	MN	PLCC	PHIL-M	68	80	254	0	3 EOS	
														500	232	0	17 EOS		
HTOL2	125C/5.75V		CY7B135-JC	M71053	9640	349612257	SPCM	4K x 8 DP	BICMOS-SM2	BiCMOS	TX	PLCC	KOREA-A	52	96	119	0		
		125C/6.50V	CY7C4265-JC	97062	9652	349616113	SPCM	16KX18 FIFO	SRAM/LOGIC-R30	CMOS	CA	PLCC	KOREA-A	68	48	1026	0		
														80	252	0	1 EOS		
														500	251	0			
HTSSL	150C/5.75V		CY7C4265-JC	96464	9706	349700756	SPCM	16KX18 FIFO	SRAM/LOGIC-R30	CMOS	MN	PLCC	PHIL-M	68	80	154	0	1 EOS	
														168	153	0	1 EOS		
HTSSL2	125C/5.75V		CY7B135-JC	M71054	9640	349612257	SPCM	4K x 8 DP	BICMOS-SM2	BiCMOS	TX	PLCC	KOREA-A	52	96	119	0		
															500	119	0		
															1000	119	0		
															2000	119	0		
PCT	121C/100%RH		CY7C136-JC	M73049	9718	349702681	SPCM	2K x 8 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	PHIL-M	52	96	77	0		
																168	77	0	
			CY7C4245-AC	M73082	9715	619701765	SPCM	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	64	96	74	0		
														168	74	0			

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DCD	TC2	-65C TO 150C	CY7C136-JC	M73048	9718	349702681	SPCM	2K x 8 DP	SRAM/LOGIC-R28	CMOS	MN	PLCC	PHIL-M	52	300 1000	48 48	0 0	
			CY7C4245-AC	M72058	9703	349700347	SPCM	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	64	300 1000	50 50	0 0	
				M73083	9729	619704796	SPCM	4Kx18 FIFO	SRAM/LOGIC-R28	CMOS	MN	TQFP	KOREA-Q	64	300 1000	50 50	0 0	
			CY7C4265-JC	96464	9706	349700756	SPCM	16KX18 FIFO	SRAM/LOGIC-R30	CMOS	MN	PLCC	PHIL-M	68	300	93	1 1	POPCORN

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MPD	HAST	140C/3.3V	CY7C1021V33-VC	97099	9721	619703242L	COMDTY	64K x16	SRAM/LOGIC-R33	CMOS	MN	SOJ	TAIWN-G	44	128	48	0				
		140C/5.5V	CY62256-SNC	97111	9720	519705439	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	MN	NSOI	INDNS-O	28	128	48	0				
								519705440	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	MN	NSOI	INDNS-O	28	128	48	0		
					M72083	9721	519705680	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	128	76	2	1	METAL DEFECT/1 UNKNOWN	
					CY7C1009-VC	M72074	9708	349700919	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	TAIWN-G	32	128	9	0		
															128	71	0				
						M73015	9709	349701198	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	TAIWN-G	32	128	77	0		
					CY7C1021-VC	97101	9721	619703241	COMDTY	64K x16	SRAM/LOGIC-R3	CMOS	MN	SOJ	TAIWN-G	44	128	48	1	1	LIFTING BOND/S
								619703241L	COMDTY	64K x16	SRAM/LOGIC-R3	CMOS	MN	SOJ	TAIWN-G	44	128	48	0		
					CY7C1021-ZSC	97205	9730	619705050	COMDTY	64K x16	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	44	128	48	2	2	UNKNOWN
					CY7C1031-JC	97153	9716	519704270	SYNCHR	64K x 18	SRAM/LOGIC-R3	CMOS	MN	PLCC	INDNS-O	52	128	44	0	2	EOS
						M71046	9652	519615077	SYNCHR	64K x 18	SRAM/LOGIC-R3	CMOS	MN	PLCC	INDNS-O	52	128	78	0		
															256	76	1	1	EOS/1 LIFTING BOND		
					CY7C1048-SC	97118	9724	619703660	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWN-G	32	128	48	0		
					CY7C1049-VC	97118	9720	619702951	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	128	45	0		
															256	44	0				
						97183	9720	619702951	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	128	45	0		
					CY7C109-VC	97201	9732	519708433	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	INDNS-O	32	128	45	0	1	EOS
						97253	9652	519615484	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	128	48	0		
						M73009	9722	519705873	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	128	77	0		
						M73042	9725	519706781	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	128	32	0		
															128	48	0				
					CY7C1329-AC	97302	9720	619703196L	SYNC	64K x 32	SRAM/LOGIC-R33	CMOS	MN	TQFP	TAIWN-G	100	128	48	0		
			CY7C185-45PC	M72070	9717	219703823	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	PDIP	ALPHA-X	28	128	78	0				
				M73024	9723	219705968	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	PDIP	ALPHA-X	28	128	78	0				
			CY7C199-SC	M72035	9715	219703326	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOIC	ALPHA-X	28	128	78	16	16	TOP SIDE DEFECT		

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MPD	HAST	140C/5.5V	CY7C199-SC	M72043	9715	219703407	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOIC	ALPHA-X	28	48	80	0		
															176	42	2 2	EOS/2 TOP SIDE DEFECT	
			CY7C199-VC	M72032	9715	219703386	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	128	21	0		
															128	56	0		
																176	49	0	
																176	49	0	
																176	49	0	
			CY7C199-ZC	M72065	9706	349700898	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	48	70	0 1	EOS	
													176	70	0				
				M72077	9709	349701549	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	128	77	0		
				M73080	9721	349703035	COMDTY	256K	SRAM/LOGIC-R3	CMOS	MN	TSOP	PHIL-M	28	128	4	0		
													128	69	0				
HTOL	150C/3.65V		CY7C1399-VC	97277	9717	619702315	SYNCHR	32K x 8	SRAM/LOGIC-R31	CMOS	MN	SOJ	PHIL-M	28	48	513	1 1	OTHERS	
															48	1080	0		
																48	520	0	
				CY7C1399-ZC	97277	9722	619702013	SYNCHR	32K x 8	SRAM/LOGIC-R31	CMOS	MN	TSOP	PHIL-M	28	48	494	0	
	150C/3.80V		CY62256V-ZC	97275	9720	349702852N	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	48	2823	0		
															28	48	2875	0	
															28	48	2693	0	
				CY7C1020V33-VC	97298	9725	619704003L	COMDTY	32K x16	SRAM/LOGIC-R3	CMOS	MN	SOJ	TAIWN-G	44	48	650	0	
				CY7C1021V33-VC	97099	9721	619703242L	COMDTY	64K x16	SRAM/LOGIC-R33	CMOS	MN	SOJ	TAIWN-G	44	80	118	0	
														500	118	0			
150C/5.75V		CY62256-SNC	97111	9720	519705439	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	MN	NSOI	INDNS-O	28	48	367	0			
														48	442	0 1	EOS		
														48	783	0			
													80	120	1 1	POLY DEFECT			
													80	140	0				
													500	119	0				

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MPD	HTOL	150C/5.75V	CY62256-SNC	97111	9720	519705439	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	MN	NSOI	INDNS-O	28	500	140	1	1	UNKNOWN
						519705440	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	MN	NSOI	INDNS-O	28	48	783	0		
															80	810	1	1	PARTICLE/1 LASER FUSE
															80	120	0		
															500	120	0		
				97232	9723	519705783	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	48	519	0		
															80	120	0		
															500	120	0		
			CY62256V-PC	97232		519706088	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	PDIP	INDNS-O	28	48	336	0		
															80	119	0		
															500	119	0		
						519706089	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	PDIP	INDNS-O	28	48	336	0		
						519706090	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	PDIP	INDNS-O	28	48	336	0		
			CY7C1021-VC	97101	9721	619703241	COMDTY	64K x16	SRAM/LOGIC-R3	CMOS	MN	SOJ	TAIWN-G	44	80	118	0		
															500	117	0	1	EOS
			CY7C1031-JC	97153	9715	519703880	SYNCHR	64K x 18	SRAM/LOGIC-R3	CMOS	MN	PLCC	INDNS-O	52	80	120	0		
															500	116	1	4	LATCH-UP/1 OTHERS
						9716	519704270	SYNCHR	64K x 18	SRAM/LOGIC-R3	CMOS	MN	PLCC	INDNS-O	52	80	117	0	
															500	116	0	9	LATCH-UP
			CY7C1048-SC	97118	9724	619703660	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWN-G	32	80	116	0		
															500	116	1	1	UNKNOWN
			CY7C1049-VC	97118	9720	619702951	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	80	113	0		
															500	111	0	2	EOS
															1000	111	0		
						9725	619704042	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	80	118	0	
															500	117	0		
						9733	619705902	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	80	447	0	
			CY7C109-VC	97201	9732	519708433	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	INDNS-O	32	48	538	0	1	EOS
															80	535	0	2	EOS
															500	535	0		
				97253	9713	519615486	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	80	260	0		
															500	259	0		

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MPD	HTS	165C/NO BIAS	CY7C1048-SC	97184	9725	619703658	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWN-G	32	1000	47	0		
			CY7C1049-VC	97118	9720	619702951	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	336 1000	46 46	0 0		
				97183	9720	619702951	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	336	46	0		
			CY7C109-VC	97201	9732	519708433	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	INDNS-O	32	336 500	46 46	0 0		
			CY7C1329-AC	97302	9720	619703196L	SYNC	64K x 32	SRAM/LOGIC-R33	CMOS	MN	TQFP	TAIWN-G	100	336	48	0		
HTSSL	150C/3.8V	150C/3.8V	CY7C1021V33-VC	97099	9721	619703242L	COMDTY	64K x16	SRAM/LOGIC-R33	CMOS	MN	SOJ	TAIWN-G	44	80 168	78 78	0 1	OTHERS	
			CY7C109-VC	97201	9732	519708433	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	INDNS-O	32	80 168	78 78	0 0		
			CY62256-SNC	97111	9720	519705439	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	MN	NSOI	INDNS-O	28	80 168	81 81	0 0		
						519705440	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	MN	NSOI	INDNS-O	28	80 168	81 81	0 0		
			CY7C1021-VC	97101	9721	619703241	COMDTY	64K x16	SRAM/LOGIC-R3	CMOS	MN	SOJ	TAIWN-G	44	76 80 168 168	76 78 74 76	0 0 0 0		
			CY7C1031-JC	97153	9715	519703880	SYNCHR	64K x 18	SRAM/LOGIC-R3	CMOS	MN	PLCC	INDNS-O	52	80 168	80 80	0 0		
						9716	519704270	SYNCHR	64K x 18	SRAM/LOGIC-R3	CMOS	MN	PLCC	INDNS-O	52	80 80 168 168	76 76 75 76	0 1 1	LATCH-UP/1 PARTICLE
			CY7C1048-SC	97118	9724	619703660	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWN-G	32	80 168 256	76 76 76	0 0 0		
			CY7C1049-VC	97118	9720	619702951	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	80 168	76 76	0 0		
						9725	619704042	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	80 168	73 77	0 0	

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MPD	HTSSL	150C/5.75V	CY7C109-VC	97253	9652	519615484	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	80 168	80 80	0 0	
					9701	519615485	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	80 168	80 80	0 0	
	HTSSL2	125C/5.75V	CY7C1031-JC	M71048	9652	519615077	SYNCHR	64K x 18	SRAM/LOGIC-R3	CMOS	MN	PLCC	INDNS-O	52	96 500 1500	120 106 106	0 0 0	1 LATCH-UP 13 EOS 9 LATCH-UP
			CY7C199-VC	M72003	9716	619702338	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	96 500 1000 2000	120 120 119 119	0 1 0 0	1 IONIC CONTAMINATION
				M72007	9715	619702274	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	96 500 1000 2000	120 117 114 114	3 2 2 1 4	2 TOPSIDE SCRATCHES 1 SPEED DEGRATION 1 TOP SIDE DEFECT 1 SPEED DEGRATION 4 TOP SIDE DEFECT
	LTOL	-30C/6.5V	CY7C1049-VC	97118	9720	619702877/	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	500	45	0	
	PCT	121C/100%RH	CY62256-SNC	M72085	9721	519705680	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	96 168	78 78	0 0	
				M73014	9720	519705368	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	96 168	78 78	0 0	
			CY62256-ZC	M73041	9715	349701906	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	MN	TSOP	INDNS-O	28	96 168	80 80	0 0	
			CY62256V-ZC	M73064	9720	349702852	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	96 168	80 80	0 0	
			CY62256V-ZI	M73040	9720	349702855	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	96 168	85 85	0 0	
				M73063	9720	349702855	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	96 168	80 77	0 0	
			CY7C1009-VC	M72039	9710	349701371	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	TAIWN-G	32	96 168	50 45	5 1	5 TOPSIDE CRACKS 1 TOPSIDE CRACKS

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MPD	PCT	121C/100%RH	CY7C1009-VC	M72075	9708	349700919	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	TAIWN-G	32	96 168	80 80	0 0	
				M73017	9709	349701198	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	TAIWN-G	32	96 168	77 75	2 0	2 TOPSIDE CRACKS
			CY7C109-VC	M73011	9722	519705873	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	96 168	78 78	0 0	
			CY7C1399-ZC	M73051	9617	349605229	SYNCHR	32K x 8	SRAM/LOGIC-R31	CMOS	CA	TSOP	KOREA-H	28	96 168	80 80	0 0	
			CY7C185-45PC	M72072	9717	219703823	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	PDIP	ALPHA-X	28	96 168	78 74	0 0	
				M73026	9723	219705968	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	PDIP	ALPHA-X	28	96 168	77 77	0 0	
			CY7C186-ZC	M73020	9723	619703886	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	TSOP	KOREA-Q	32	96 168	77 77	0 0	
			CY7C199-SC	M72036	9715	219703326	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOIC	ALPHA-X	28	96 168	78 55	0 0	1 LASER FUSE INC. SERVER
			CY7C199-VC	M73005	9720	219704818	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	96 168	77 77	0 0	
				M73008	9724	619703780	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	96 168	78 78	0 0	
			CY7C199-ZC	M72078	9709	349701549	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	168	78	0	
				M73023	9720	619703287	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	28	96 168	77 77	0 0	
				M73078	9721	349703035	COMDTY	256K	SRAM/LOGIC-R3	CMOS	MN	TSOP	PHIL-M	28	96 168	76 76	0 0	
	T/S	-55C TO 150C	CY7C1021-ZSC	97205	9730	619705050	COMDTY	64K x16	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	44	100 200	48 48	0 0	
			CY7C1049-VC	97183	9720	619702951	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	100 200	45 45	0 0	
			CY7C1329-AC	97302	9720	619703196L	SYNC	64K x 32	SRAM/LOGIC-R33	CMOS	MN	TQFP	TAIWN-G	100	100 200	48 48	0 0	

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MPD	TC2	-65C TO 150C	CY62256-SNC	97111	9720	519705439	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	MN	NSOI	INDNS-O	28	300 1000	47 47	0	1 1 TOPSIDE CRACKS
						519705440	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	MN	NSOI	INDNS-O	28	300 1000	48 48	0	
				M72082	9721	519705680	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	300 1000	48 48	0	
				M73013	9720	519705368	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	300	48	0	
			CY7C1009-VC	M72037	9710	349701371	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	TAIWN-G	32	300 1000	50 50	0	
				M72073	9708	349700919	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	TAIWN-G	32	300 1000	50 50	0	
				M73016	9709	349701198	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	TAIWN-G	32	300	47	0	
			CY7C1021-VC	97101	9721	619703241	COMDTY	64K x16	SRAM/LOGIC-R3	CMOS	MN	SOJ	TAIWN-G	44	300 1000	48 48	0	
			CY7C1021-ZSC	97205	9718	619702417	COMDTY	64K x16	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	44	300 1000	48 48	0	
					9729	619705048	COMDTY	64K x16	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	44	300 1000	48 48	0	
					9730	619705049	COMDTY	64K x16	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	44	1000	48	0	
						619705050	COMDTY	64K x16	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	44	300	39	0	
			CY7C1021V33-VC	97099	9721	619703242L	COMDTY	64K x16	SRAM/LOGIC-R33	CMOS	MN	SOJ	TAIWN-G	44	300 703 1000	48 48 48	0	
			CY7C1031-JC	97153	9715	519703879	SYNCHR	64K x 18	SRAM/LOGIC-R3	CMOS	MN	PLCC	INDNS-O	52	300	48	0	
						519703880	SYNCHR	64K x 18	SRAM/LOGIC-R3	CMOS	MN	PLCC	INDNS-O	52	300 1000	50 50	0	
					9716	519704270	SYNCHR	64K x 18	SRAM/LOGIC-R3	CMOS	MN	PLCC	INDNS-O	52	300	47	0	
			CY7C1048-SC	97118	9723	619702975	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWN-G	32	300 703	45 45	0	

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MPD	TC2	-65C TO 150C	CY7C1048-SC	97118	9723	619702975	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOIC	TAIWN-G	32	1000	45	0				
			CY7C1049-VC	97118	9720	619702877	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	300	45	0				
									619702951	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	300	46	0	
																1000	46	0			
							9725	619704042	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	300	45	0		
																1000	45	0			
						97183		619703003	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	300	45	0		
																1000	45	0			
							9720	619702877	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	300	45	0		
																1000	45	0			
									619702951	COMDTY	512K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	KOREA-L	36	300	46	0	
						CY7C109-VC	97072	9724	519706453	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	300	48	1	1 OTHERS
							97201	9732	519708433	COMDTY	128K x 8	SRAM/LOGIC-R32	CMOS	MN	SOJ	INDNS-O	32	300	46	0	
																1000	46	0			
							97253	9652	519615484	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	300	48	0	
																1000	48	0			
									519615487	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	300	48	0	
							9701	519615485	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	INDNS-O	32	300	48	0		
						CY7C1329-AC	97302	9720	619703196L	SYNC	64K x 32	SRAM/LOGIC-R33	CMOS	MN	TQFP	TAIWN-G	100	300	45	0	1 BROKEN PIN
																	300	48	0		
														300	48	0					
														1000	43	0					
														1000	48	0					
														1000	48	0					
			CY7C1335-AC	M72040	9710	619701129	SYNCHR	32K x 32	SRAM/LOGIC-R33	CMOS	MN	TQFP	TAIWAN-G	100	300	50	0				
														1000	50	0					
			CY7C1399-ZC	M73002	9645	349613772	SYNCHR	32K x 8	SRAM/LOGIC-R31	CMOS	CA	TSOP	PHIL-M	28	300	50	0				
														1000	50	0					
			CY7C185-45PC	M73025	9723	219705968	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	PDIP	ALPHA-X	28	300	48	0				
														1000	48	0					
			CY7C186-ZC	M72028	9713	619701453	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	TSOP	KOREA-Q	32	300	50	0				

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MPD	TC2	-65C TO 150C	CY7C186-ZC	M72028	9713	619701453	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	TSOP	KOREA-Q	32	1000	50	0					
				M73018	9723	619703886	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	TSOP	KOREA-Q	32	300 1000	48 48	0 0					
			CY7C199-12VC	97072	9706	619700374	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	300 1000	48 48	0 0					
						619700375	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	300 1000	48 48	0 1	1 UNKNOWN				
			CY7C199-SC	M72034	9715	219703326	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOIC	ALPHA-X	28	300 1000	50 50	0 0					
			CY7C199-VC	M72031	9715	219703386	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	300 1000	46 46	0 0					
				M73004	9720	219704818	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	ALPHA-X	28	300	48	0					
				M73007	9724	619703780	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	300 1000	48 48	0 0					
			CY7C199-ZC	M72076	9709	349701549	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	PHIL-M	28	300 1000	50 50	0 0					
				M73022	9720	619703287	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	TSOP	KOREA-H	28	300 1000	48 47	0 0					
			TEV	0 READ POINT		CY62256-SNC	M73037	9720	519705368	COMDTY	32K x 8	SRAM/LOGIC-R32	CMOS	CA	NSOI	INDNS-O	28	-5 25 85	120 120 120	0 0 0		
							CY7C1009-VC	M74014	9732	619705971	COMDTY	256K x 4	SRAM/LOGIC-R28	CMOS	MN	SOJ	CSPI-R	32	-5 25 85	116 116 116	0 0 0	
								CY7C109-VC	M73036	9722	519705873	COMDTY	128K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	TAIWN-G	32	-5 25 85	120 120 120	0 0 0
CY7C1399-VC	M74038	9727				619704667	SYNCHR	32K x 8	SRAM/LOGIC-R31	CMOS	MN	SOJ	PHIL-M	28	-5 25 85	116 116 116	0 0 0					
CY7C185-45PC	M72067	9717				219703823	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	PDIP	ALPHA-X	28	-5 25	120 120	0 0					

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MPD	TEV	0 READ POINT	CY7C185-45PC	M72067	9717	219703823	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	PDIP	ALPHA-X	28	85	120	0				
				M73027	9723	219705968	COMDTY	SML/64K	SRAM/LOGIC-R21	CMOS	TX	PDIP	ALPHA-X	28	-5	119	0				
																25	119	0			
																85	119	0			
																	25	120	0		
																	85	120	0		
						CY7C199-VC	M73031	9724	619703780	COMDTY	32K x 8	SRAM/LOGIC-R28	CMOS	MN	SOJ	PHIL-M	28	-5	120	0	
																	25	120	0		
																	85	120	0		
																		-5	116	0	
																		25	116	0	
																		85	116	0	
			CY7C199-ZC	M74044	9729	619705121	COMDTY	256K	SRAM/LOGIC-R3	CMOS	MN	SOJ	CSPI-R	28	-5	116	0				
															25	116	0				
															85	116	0				
																25	117	0			
															85	116	0				
																25	117	0			

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NMD	DRET	165C/NO BIAS	CY27C010-PC	M72011	9707	349700791	PROM	128K x 8	FAMOS-P26	CMOS	TX	PDIP	KOREA-H	32	168 1000	78 78	0 0	
	DRET2	250C/NO BIAS	CY27H010-WC	M73067	9727	219706861	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	32	168 1000	78 78	0 0	
	HAST	140C/5.5V	CY27C010-PC	M72012	9707	349700791	PROM	128K x 8	FAMOS-P26	CMOS	TX	PDIP	KOREA-H	32	128 128	30 48	0 0	
	HTOL2	125C/5.75V	CY27H512-JC	M71015	9651	219615860	PROM	64K x 8	FAMOS-P26	CMOS	TX	PLCC	ALPHA-X	32	96 500 1000 2000	118 115 115 115	1 2 0 0	LATCH-UP/1 UNKNOWN
	TC2	-65 TO 150C	CY27H010-WC	M72062	9704	219700663	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	32	100 1000	50 50	0 0	
				M73057	9726	219706752	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	32	100 1000	48 48	0 0	
				M73066	9727	219706861	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	32	100	48	0	
						219706861/	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	32	1000	48	0	
	TEV	0 READ POINT	CY27H010-WC	M73068	9727	219706861	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	32	25	120	0	
						219706861/	PROM	128K x 8	FAMOS-P26	CMOS	TX	WCER	ALPHA-X	32	85	119	0	

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 Quarterly Reliability Report
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Division	Test	Test Condition	Device	Eval#	D/C	Assembly Lot No	Function	Description	Technology	Process	Wfr Loc	Pkg type	Assy Loc	No Pin	Dura tion	Qty Test	Qty Fail	Fail Mode			
PPD	DRET	165C/NO BIAS	CY7C374I-JC	M71075	9643	349613266	FLASH	128 MCEL FL	FLASH-FL28D	CMOS	TX	PLCC	KOREA-A	84	168 1000	77 77	0 1	UNKNOWN			
				M72050	9715	219703283	FLASH	128 MCEL FL	FLASH-FL28D	CMOS	TX	PLCC	ALPHA-X	84	168 1000	78 78	0 0				
HAST	130C/5.5V	140C/3.6V	CY7C375U-AC	M71090	9652	349615541	FLASH	128 MCEL FL	FLASH-FL28D	CMOS	TX	TQFP	KOREA-Q	160	128	49	1	BROKEN BOND NECK			
			CY74FCT163952TP	96494	9709	349701564	FCT	16 BIT REG.	SRAM/LOGIC-R3	CMOS	MN	SSOP	MALAY-U	56	128	46	0	EOS			
			CY7C374I-JC	M72047	9715	219703283	FLASH	128 MCEL FL	FLASH-FL28D	CMOS	TX	PLCC	ALPHA-X	84	128 128 128 128	15 16 27 27	0 0 0 0				
			CY7C375U-AC	M71090	9652	349615541	FLASH	128 MCEL FL	FLASH-FL28D	CMOS	TX	TQFP	KOREA-Q	160	128	26	0				
HTOL	140C/5.75V	150C/3.6V	CY7C342B-JC	97254	9720	219704671	MAX	REPROG.PAL	FAMOS-P26	CMOS	TX	PLCC	ALPHA-X	68	24 48	166 166	0 0				
						219704672	MAX	REPROG.PAL	FAMOS-P26	CMOS	TX	PLCC	ALPHA-X	68	24 48	167 167	0 0				
						219704945	MAX	REPROG.PAL	FAMOS-P26	CMOS	TX	PLCC	ALPHA-X	68	24 48	167 163	0 0				
						9729	21970600V1	MAX	REPROG.PAL	FAMOS-P26	CMOS	TX	PLCC	ALPHA-X	68	72	192	0			
						CY7C346-HMB	97316	9731	219708428	MAX	REPROG.PAL	FAMOS-P20	CMOS	TX	CERQ	ALPHA-X	84	72	132	0	
						CY7C346-RMB	97316	9731	219708195P	MAX	REPROG.PAL	FAMOS-P20	CMOS	TX	WPGA	ALPHA-X	100	72	185	0	
									9732	219708446P	MAX	REPROG.PAL	FAMOS-P20	CMOS	TX	WPGA	ALPHA-X	100	72	178	0
			CY74FCT163952TP	96494	9709	349701564	FCT	16 BIT REG.	SRAM/LOGIC-R3	CMOS	MN	SSOP	MALAY-U	56	48	894	0				
			CY74FCT163952TP	96494	9709	349701564	FCT	16 BIT REG.	SRAM/LOGIC-R3	CMOS	MN	SSOP	MALAY-U	56	80 500	128 128	0 0				
HTOL2	125C/5.75	125C/5.75V	CY7C372-JC	97267	9722	349703281	FLASH	64-MCEL FL	FLASH-FL22D	CMOS	CA	PLCC	PHIL-M	44	48 96	203 203	0 0				
			CY7C372-JC	97267	9722	349703282P	FLASH	64-MCEL FL	FLASH-FL22D	CMOS	CA	PLCC	PHIL-M	44	48 96	221 221	0 0				

